

scanning electron microscopy sample preparation

Scanning Electron Microscopy Sample Preparation: A Detailed Guide for Optimal Imaging

scanning electron microscopy sample preparation is a crucial step that directly influences the quality and accuracy of the images obtained. Whether you're a seasoned researcher or a curious beginner, understanding how to prepare your samples can be the difference between blurry, uninformative images and crisp, detailed micrographs revealing fascinating structures. This article explores the essentials of preparing samples for scanning electron microscopy (SEM), covering techniques, tips, and considerations that can help you achieve outstanding results.

Why Is Sample Preparation Important in SEM?

Before diving into the specifics, it's worth understanding why sample preparation matters so much in SEM. Unlike light microscopy, SEM uses a focused beam of electrons to scan the specimen's surface. This means that the sample must be stable under a high vacuum and conductive enough to prevent charging effects. Improperly prepared samples can lead to image distortion, loss of fine details, or even damage to the microscope itself.

Moreover, sample preparation influences the contrast, resolution, and the ability to observe surface morphology or elemental composition. Tailoring your preparation methods to the type of material—whether biological tissue, metals, polymers, or ceramics—is essential for meaningful analysis.

Key Steps in Scanning Electron Microscopy Sample Preparation

1. Fixation and Stabilization

For biological specimens, fixation is often the first step. This process preserves the natural structure by cross-linking proteins and halting biological activity. Chemical fixatives like glutaraldehyde or formaldehyde are commonly used, sometimes followed by osmium tetroxide to enhance membrane contrast.

In non-biological samples such as minerals or metals, fixation is generally not required. Instead, stabilization might involve embedding fragile samples in resins to prevent deformation during handling.

2. Dehydration

Since SEM requires a vacuum environment, any water in the sample can evaporate and distort the specimen. Dehydration removes water, preserving structural integrity. For biological samples, this often involves passing the specimen through a graded series of ethanol or acetone solutions, gradually replacing water with an organic solvent.

Critical point drying (CPD) is a popular technique to avoid surface tension damage during drying. CPD replaces the dehydration solvent with liquid CO₂, which is then brought above its critical point, allowing it to become a gas without passing through a liquid phase. This preserves delicate structures without collapse or shrinkage.

3. Mounting the Sample

Once dehydrated, samples are mounted on specialized SEM stubs using conductive adhesives such as carbon tape or silver paste. Proper mounting ensures mechanical stability and electrical conductivity, both vital for reducing charging effects under the electron beam.

Mounting orientation is also important; positioning the area of interest towards the detector can improve image quality.

4. Coating for Conductivity

Most samples, especially biological and insulating materials, need a conductive coating to prevent charging and improve electron emission. Thin layers of metals like gold, platinum, or palladium are deposited using sputter coating or evaporation methods.

The thickness of the coating is critical—too thick, and it may obscure fine surface details; too thin, and charging artifacts may persist. Typically, coatings range from 2 to 20 nanometers, depending on the application.

Special Considerations for Different Sample Types

Biological Samples

Biological specimens are among the most challenging to prepare due to their high water content and

delicate structures. Beyond fixation and dehydration, some researchers use freeze-drying or cryo-SEM techniques to observe samples in a near-native state.

Cryo-SEM involves rapidly freezing the sample and imaging it at low temperatures, reducing preparation artifacts. However, it requires specialized equipment and expertise.

Metals and Alloys

Metal specimens are generally easier to prepare because they are inherently conductive and vacuum-stable. Polishing and etching are common steps to reveal microstructures such as grain boundaries or phase distributions.

Sometimes, samples are ion-milled to produce an ultra-smooth surface free of mechanical artifacts, which enhances imaging resolution.

Polymers and Ceramics

These materials often have insulating properties that necessitate conductive coatings. Additionally, polymers can be sensitive to electron beam damage, so low voltage imaging or environmental SEM (ESEM) modes may be preferred to minimize degradation.

Ceramics may require fracture surfaces to be examined, highlighting microstructural features such as porosity or cracks.

Tips for Achieving the Best SEM Sample Preparation

- **Understand your sample:** Tailor preparation protocols to the material type and the features you want to study.
- **Minimize contamination:** Clean samples and tools thoroughly to avoid artifacts or misleading signals.
- **Use appropriate fixation and dehydration:** For biological samples, carefully control chemical concentrations and exposure times to preserve ultrastructure.
- **Optimize coating thickness:** Experiment with sputtering times to balance conductivity and surface detail visibility.

- **Handle samples carefully:** Avoid mechanical stress that could alter morphology before imaging.
- **Consider alternative SEM modes:** Techniques like low vacuum SEM or cryo-SEM can reduce preparation requirements and artifacts for sensitive materials.

Common Challenges and How to Overcome Them

One frequent issue is “charging,” where non-conductive samples accumulate electrons, causing bright spots or image distortion. Proper coating and grounding are essential to mitigate this.

Another challenge is dehydration-induced shrinkage or collapse, particularly in soft biological tissues. Critical point drying or freeze-substitution methods can help maintain native structures.

Sample contamination from dust, oils, or residues can obscure details or introduce misleading features. Working in clean environments and using gloves can reduce this risk.

Finally, beam damage is a concern for beam-sensitive materials. Reducing electron accelerating voltage, shortening exposure times, and using detectors optimized for low voltage can prolong sample integrity.

Emerging Techniques in SEM Sample Preparation

Advancements in SEM technology are influencing preparation methods. Environmental SEM allows imaging of hydrated or uncoated samples in a low vacuum, reducing the need for extensive dehydration or coating. Similarly, focused ion beam (FIB) systems enable site-specific sample thinning and preparation, allowing for high-resolution imaging of internal structures.

Automated preparation systems and improved cryo-techniques are also making it easier to prepare complex biological samples with minimal artifacts.

Exploring these innovations can help researchers push the boundaries of what SEM can reveal.

Throughout the process of scanning electron microscopy sample preparation, attention to detail and understanding material properties are key. With practice, experimentation, and the right protocols, SEM can unveil stunning micro- and nanoscale details that drive scientific discovery and innovation.

Frequently Asked Questions

What are the basic steps involved in sample preparation for scanning electron microscopy (SEM)?

The basic steps for SEM sample preparation include fixation, dehydration, drying (usually critical point drying), mounting the sample on a stub, and coating with a conductive material such as gold or carbon to prevent charging under the electron beam.

Why is coating necessary for SEM samples and which materials are commonly used?

Coating is necessary to make non-conductive samples conductive, preventing charging and improving image quality under the electron beam. Common coating materials include gold, platinum, palladium, and carbon.

How do you prepare biological samples for SEM imaging?

Biological samples are typically fixed with glutaraldehyde or formaldehyde, post-fixed with osmium tetroxide, dehydrated through a graded ethanol series, dried (often by critical point drying), mounted on a stub, and coated with a conductive layer before SEM imaging.

What challenges are faced when preparing wet or hydrated samples for SEM?

Wet or hydrated samples can collapse or distort due to vacuum conditions in SEM. To overcome this, samples are dehydrated carefully, often using critical point drying or freeze-drying techniques to preserve morphology.

Can SEM be performed on non-conductive materials without coating?

While it is possible to image non-conductive materials without coating using low vacuum or environmental SEM modes, coating is generally preferred to enhance resolution and reduce charging effects.

What is critical point drying and why is it important in SEM sample preparation?

Critical point drying is a method used to remove liquid from a sample without surface tension effects that can cause structural damage. It replaces water with a transitional fluid like CO₂ and then brings it to its critical point, preserving fine structures in the sample for SEM imaging.

How does sample size affect SEM preparation and imaging?

Sample size must be compatible with the SEM chamber; typically, samples are trimmed or sectioned to fit. Larger samples may require special mounting techniques, and uneven surfaces may need polishing to obtain clear images.

Additional Resources

Scanning Electron Microscopy Sample Preparation: Techniques and Best Practices

scanning electron microscopy sample preparation is a critical step in obtaining high-quality images and meaningful data from SEM analysis. The process involves a series of meticulous procedures aimed at preserving the integrity of the sample while making it compatible with the vacuum and electron beam environment of the microscope. Proper preparation affects resolution, contrast, and the overall reliability of observations, making it indispensable for researchers across materials science, biology, geology, and semiconductor industries.

Understanding the nuances of SEM sample preparation is essential, as improper techniques can introduce artifacts, charging effects, or even sample damage. This article thoroughly examines the various methods and considerations in preparing samples for scanning electron microscopy, highlighting the importance of tailoring approaches to specific specimen types and research goals.

Fundamentals of SEM Sample Preparation

To appreciate the complexity of SEM sample preparation, one must first consider the operational environment of the microscope. SEM operates under high vacuum conditions, using an electron beam to scan the specimen surface. Since electrons interact strongly with matter, samples must be conductive or coated to prevent charging. Additionally, the vacuum environment demands that samples be free of volatile substances that might evaporate under low pressure.

Sample preparation, therefore, involves multiple objectives:

- Stabilizing the specimen physically and chemically
- Ensuring electrical conductivity
- Maintaining surface details and morphology
- Minimizing contamination and artifacts

Meeting these requirements varies significantly depending on whether the sample is metallic, biological, polymeric, or geological in nature.

Sample Cleaning and Fixation

Prior to any specialized treatment, cleaning is paramount to remove dust, oils, or residues that can obscure imaging. For biological specimens, chemical fixation using agents such as glutaraldehyde and osmium tetroxide is routine to preserve cellular structures by cross-linking proteins and lipids. Fixation prevents degradation and shrinkage during subsequent dehydration steps.

In contrast, metallic or crystalline samples often require minimal cleaning, typically involving ultrasonic baths or solvent rinses to eliminate surface contaminants.

Dehydration Techniques

Biological samples, rich in water content, must undergo dehydration to survive the vacuum of SEM without structural collapse. Traditional dehydration employs graded ethanol series, gradually replacing water with ethanol to mitigate osmotic shock. Following this, critical point drying (CPD) is widely regarded as the gold standard, replacing ethanol with liquid CO₂, which is then converted to gas at its critical point, avoiding surface tension effects that could damage delicate structures.

Alternative methods like freeze-drying or freeze-substitution are employed for particularly sensitive samples, offering improved preservation but requiring specialized equipment.

Embedding and Sectioning

For samples requiring internal structural analysis, embedding in resin followed by ultramicrotomy allows thin sectioning. This approach is especially useful in biological and polymer studies where cross-sectional imaging reveals subcellular or compositional details.

Embedding stabilizes fragile samples, while sectioning ensures electron transparency for transmission electron microscopy (TEM) or reveals cross-sectional morphology for SEM.

Enhancing Conductivity: Coating and Mounting

Non-conductive samples pose a challenge for SEM imaging due to electron charging, which can distort images and reduce resolution. Coating specimens with a thin conductive layer is a widely adopted solution.

Common Coating Materials

- **Gold and Gold-Palladium Alloy:** Provides excellent conductivity and fine grain size, ideal for high-resolution imaging.
- **Carbon:** Offers a conductive layer with minimal interference in X-ray spectroscopy, favored for elemental analysis.
- **Platinum and Iridium:** Used for ultra-fine coatings, particularly when detailed surface topography is crucial.

Sputter coating and thermal evaporation are the prevalent techniques to deposit these layers, with sputtering offering better control over thickness and uniformity.

Sample Mounting Strategies

Proper mounting ensures stability under the electron beam and facilitates electrical grounding. Conductive adhesives such as carbon tape or silver paint are standard for attaching samples to aluminum stubs. The choice depends on sample size, fragility, and the need for electrical continuity.

For powders or loose particles, embedding in a resin matrix or using double-sided carbon tape helps prevent displacement during vacuum pumping.

Advanced Preparation Methods for Specialized Samples

Certain materials require tailored approaches to maximize SEM imaging quality and data integrity.

Environmental SEM and Cryo-SEM

Environmental SEM (ESEM) allows imaging of hydrated or non-conductive samples without extensive preparation by maintaining a low vacuum with water vapor. This reduces the need for dehydration and

coating but offers lower resolution compared to conventional SEM.

Cryo-SEM involves rapid freezing of samples to preserve native hydrated states, followed by fracturing and sublimation in vacuum. This technique is invaluable for biological tissues, hydrogels, and emulsions where traditional preparation would alter morphology.

Ion Beam Milling and Focused Ion Beam (FIB) Techniques

For site-specific sample preparation, focused ion beam milling enables precision thinning and cross-sectioning. FIB is particularly useful in semiconductor failure analysis, materials science, and nanotechnology, allowing preparation of electron-transparent lamellae or exposing subsurface features without mechanical damage.

Challenges and Considerations in SEM Sample Preparation

Despite advances, SEM sample preparation presents several challenges:

- **Artifacts:** Chemical fixation or coating can introduce artifacts that misrepresent native structures.
- **Sample Damage:** Dehydration and vacuum exposure may cause shrinkage, cracking, or collapse, especially in biological specimens.
- **Time and Resource Intensive:** Comprehensive preparation protocols can be laborious and require specialized equipment.
- **Balancing Conductivity and Resolution:** Excessive coating thickness may obscure fine details, while insufficient coating leads to charging.

Selecting optimal preparation techniques necessitates a balance between preserving sample fidelity and achieving the required imaging quality. Experimentation and protocol optimization are often essential, especially when dealing with novel or complex materials.

Throughout these processes, maintaining cleanliness and preventing contamination is critical, as even microscopic dust or residues can degrade SEM performance.

Scanning electron microscopy sample preparation remains a dynamic field, evolving alongside advances in instrumentation and materials science. Researchers continue to refine methods to accommodate increasingly

diverse and sensitive samples, ensuring SEM retains its status as a powerful tool for nanoscale characterization across disciplines.

Scanning Electron Microscopy Sample Preparation

scanning electron microscopy sample preparation: *Handbook of Sample Preparation for Scanning Electron Microscopy and X-Ray Microanalysis* Patrick Echlin, 2011-04-14 Scanning electron microscopy (SEM) and x-ray microanalysis can produce magnified images and in situ chemical information from virtually any type of specimen. The two instruments generally operate in a high vacuum and a very dry environment in order to produce the high energy beam of electrons needed for imaging and analysis. With a few notable exceptions, most specimens destined for study in the SEM are poor conductors and composed of beam sensitive light elements containing variable amounts of water. In the SEM, the imaging system depends on the specimen being sufficiently electrically conductive to ensure that the bulk of the incoming electrons go to ground. The formation of the image depends on collecting the different signals that are scattered as a consequence of the high energy beam interacting with the sample. Backscattered electrons and secondary electrons are generated within the primary beam-sample interactive volume and are the two principal signals used to form images. The backscattered electron coefficient (η_b) increases with increasing atomic number of the specimen, whereas the secondary electron coefficient (η_s) is relatively insensitive to atomic number. This fundamental difference in the two signals can have an important effect on the way samples may need to be prepared. The analytical system depends on collecting the x-ray photons that are generated within the sample as a consequence of interaction with the same high energy beam of primary electrons used to produce images.

scanning electron microscopy sample preparation: *Transmission Electron Microscopy Sample Preparation* Rajender Singh, 2025-02-10 This book is a thorough guide tailored for researchers, academics, and practitioners immersed in the intricate world of Transmission Electron Microscopy (TEM). It offers a seamless blend of theoretical understanding and practical insights, providing readers with the essential skills to navigate the complexities of TEM sample preparation for optimal imaging. The book begins by introducing the basics of TEM operation, progressing to advanced modes, and dedicating significant attention to the nuances of sample preparation. Each chapter serves as a stepping stone, guiding readers from specimen selection to the acquisition of high-resolution micrographs. The motivation behind this book lies in addressing the practical challenges of TEM operation and sample preparation. The book bridges the gap between theory and application, offering a simplified yet scientific repository of dos and don'ts for achieving successful results in TEM sample preparation. Within these pages, readers will explore various thinning techniques, delve into the preparation of nanomaterials and biological samples, and grasp the intricacies of cryo-TEM and in-situ TEM. Along with troubleshooting guidance to common pitfalls, the book also provides practical tips for overcoming challenges in the sample preparation process. The book also addresses the importance of properly prepared TEM samples, emphasizing the often-underestimated role they play in unlocking the full potential of TEM imaging. Real-world case studies showcase the impact of high-quality sample preparation across diverse research fields. This book is not just an informative guide; it is a journey of transformation and enlightenment, empowering the reader with the confidence and expertise needed for precise sample preparation and quality imaging.

scanning electron microscopy sample preparation: *A Beginners' Guide to Scanning Electron Microscopy* Anwar Ul-Hamid, 2018-10-26 This book was developed with the goal of providing an easily understood text for those users of the scanning electron microscope (SEM) who have little or no background in the area. The SEM is routinely used to study the surface structure

and chemistry of a wide range of biological and synthetic materials at the micrometer to nanometer scale. Ease-of-use, typically facile sample preparation, and straightforward image interpretation, combined with high resolution, high depth of field, and the ability to undertake microchemical and crystallographic analysis, has made scanning electron microscopy one of the most powerful and versatile techniques for characterization today. Indeed, the SEM is a vital tool for the characterization of nanostructured materials and the development of nanotechnology. However, its wide use by professionals with diverse technical backgrounds—including life science, materials science, engineering, forensics, mineralogy, etc., and in various sectors of government, industry, and academia—emphasizes the need for an introductory text providing the basics of effective SEM imaging. A Beginners' Guide to Scanning Electron Microscopy explains instrumentation, operation, image interpretation and sample preparation in a wide ranging yet succinct and practical text, treating the essential theory of specimen-beam interaction and image formation in a manner that can be effortlessly comprehended by the novice SEM user. This book provides a concise and accessible introduction to the essentials of SEM includes a large number of illustrations specifically chosen to aid readers' understanding of key concepts highlights recent advances in instrumentation, imaging and sample preparation techniques offers examples drawn from a variety of applications that appeal to professionals from diverse backgrounds.

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scanning electron microscopy sample preparation: Sample Preparation Handbook for Transmission Electron Microscopy Jeanne Ayache, Luc Beaunier, Jacqueline Boumendil, Gabrielle Ehret, Danièle Laub, 2010-06-08 Successful transmission electron microscopy in all of its manifestations depends on the quality of the specimens examined. Biological specimen preparation protocols have usually been more rigorous and time consuming than those in the physical sciences. For this reason, there has been a wealth of scientific literature detailing specific preparation steps and numerous excellent books on the preparation of biological thin specimens. This does not mean to imply that physical science specimen preparation is trivial. For the most part, most physical science thin specimen preparation protocols can be executed in a matter of a few hours using straightforward steps. Over the years, there has been a steady stream of papers written on various aspects of preparing thin specimens from bulk materials. However, aside from several seminal textbooks and a series of book compilations produced by the Material Research Society in the 1990s, no recent comprehensive books on thin specimen preparation have appeared until this present work, first in

French and now in English. Everyone knows that the data needed to solve a problem quickly are more important than ever. A modern TEM laboratory with supporting SEMs, light microscopes, analytical spectrometers, computers, and specimen preparation equipment is an investment of several million US dollars. Fifty years ago, electropolishing, chemical polishing, and replication methods were the principal specimen preparation methods.

scanning electron microscopy sample preparation: *Electron Microscopy and Analysis, Third Edition* Peter J. Goodhew, John Humphreys, Richard Beanland, 2000-11-30 *Electron Microscopy and Analysis* deals with several sophisticated techniques for magnifying images of very small objects by large amounts - especially in a physical science context. It has been ten years since the last edition of *Electron Microscopy and Analysis* was published and there have been rapid changes in this field since then. The authors have vastly updated their very successful second edition, which is already established as an essential laboratory manual worldwide, and they have incorporated questions and answers in each chapter for ease of learning. Equally as relevant for material scientists and bioscientists, this third edition is an essential textbook.

scanning electron microscopy sample preparation: *Scanning Electron Microscopy for the Life Sciences* Heide Schatten, 2013 A guide to modern scanning electron microscopy instrumentation, methodology and techniques, highlighting novel applications to cell and molecular biology.

scanning electron microscopy sample preparation: *Scanning Electron Microscopy, X-Ray Microanalysis, and Analytical Electron Microscopy* Charles E. Lyman, Dale E. Newbury, Joseph Goldstein, David B. Williams, Alton D. Romig Jr., John Armstrong, Patrick Echlin, Charles Fiori, David C. Joy, Eric Lifshin, Klaus-Rüdiger Peters, 2012-12-06 During the last four decades remarkable developments have taken place in instrumentation and techniques for characterizing the microstructure and microcomposition of materials. Some of the most important of these instruments involve the use of electron beams because of the wealth of information that can be obtained from the interaction of electron beams with matter. The principal instruments include the scanning electron microscope, electron probe x-ray microanalyzer, and the analytical transmission electron microscope. The training of students to use these instruments and to apply the new techniques that are possible with them is an important function, which has been carried out by formal classes in universities and colleges and by special summer courses such as the ones offered for the past 19 years at Lehigh University. Laboratory work, which should be an integral part of such courses, is often hindered by the lack of a suitable laboratory workbook. While laboratory workbooks for transmission electron microscopy have been in existence for many years, the broad range of topics that must be dealt with in scanning electron microscopy and microanalysis has made it difficult for instructors to devise meaningful experiments. The present workbook provides a series of fundamental experiments to aid in hands-on learning of the use of the instrumentation and the techniques. It is written by a group of eminently qualified scientists and educators. The importance of hands-on learning cannot be overemphasized.

scanning electron microscopy sample preparation: *Sample Preparation Handbook for Transmission Electron Microscopy* Jeanne Ayache, Luc Beaunier, Jacqueline Boumendil, Gabrielle Ehret, Danièle Laub, 2010-07-03 Successful transmission electron microscopy in all of its manifestations depends on the quality of the specimens examined. Biological specimen preparation protocols have usually been more rigorous and time consuming than those in the physical sciences. For this reason, there has been a wealth of scientific literature detailing specific preparation steps and numerous excellent books on the preparation of biological thin specimens. This does not mean to imply that physical science specimen preparation is trivial. For the most part, most physical science thin specimen preparation protocols can be executed in a matter of a few hours using straightforward steps. Over the years, there has been a steady stream of papers written on various aspects of preparing thin specimens from bulk materials. However, aside from several seminal textbooks and a series of book compilations produced by the Material Research Society in the 1990s, no recent comprehensive books on thin specimen preparation have appeared until this present work, first in

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scanning electron microscopy sample preparation: Scanning Electron Microscopy and X-Ray Microanalysis Joseph Goldstein, Dale E. Newbury, David C. Joy, Charles E. Lyman, Patrick Echlin, Eric Lifshin, Linda Sawyer, J.R. Michael, 2012-12-06 In the decade since the publication of the second edition of *Scanning Electron Microscopy and X-Ray Microanalysis*, there has been a great expansion in the capabilities of the basic scanning electron microscope (SEM) and the x-ray spectrometers. The emergence of the variable-pressure/environmental SEM has enabled the observation of samples containing water or other liquids or vapor and has allowed for an entirely new class of dynamic experiments, that of direct observation of chemical reactions in situ. Critical advances in electron detector technology and computer-aided analysis have enabled structural (crystallographic) analysis of specimens at the micrometer scale through electron backscatter diffraction (EBSD). Low-voltage operation below 5 kV has improved x-ray spatial resolution by more than an order of magnitude and provided an effective route to minimizing sample charging. High-resolution imaging has continued to develop with a more thorough understanding of how secondary electrons are generated. The field emission gun SEM, with its high brightness, advanced electron optics, which minimizes lens aberrations to yield an effective nanometer-scale beam, and "through-the-lens" detector to enhance the measurement of primary-beam-excited secondary electrons, has made high-resolution imaging the rule rather than the exception. Methods of x-ray analysis have evolved allowing for better measurement of specimens with complex morphology: multiple thin layers of different compositions, and rough specimens and particles. Digital mapping has transformed classic x-ray area scanning, a purely qualitative technique, into fully quantitative compositional mapping.

scanning electron microscopy sample preparation: Biological Field Emission Scanning Electron Microscopy, 2 Volume Set Roland A. Fleck, Bruno M. Humbel, 2019-04-29 The go-to resource for microscopists on biological applications of field emission gun scanning electron microscopy (FEGSEM) The evolution of scanning electron microscopy technologies and capability over the past few years has revolutionized the biological imaging capabilities of the microscope—giving it the capability to examine surface structures of cellular membranes to reveal the organization of individual proteins across a membrane bilayer and the arrangement of cell cytoskeleton at a nm scale. Most notable are their improvements for field emission scanning electron microscopy (FEGSEM), which when combined with cryo-preparation techniques, has provided insight into a wide range of biological questions including the functionality of bacteria and viruses. This full-colour, must-have book for microscopists traces the development of the biological field emission scanning electron microscopy (FEGSEM) and highlights its current value in biological research as well as its future worth. *Biological Field Emission Scanning Electron Microscopy* highlights the present capability of the technique and informs the wider biological science community of its application in basic biological research. Starting with the theory and history of FEGSEM, the book offers chapters covering: operation (strengths and weakness, sample selection, handling, limitations, and preparation); Commercial developments and principals from the major FEGSEM manufacturers (Thermo Scientific, JEOL, HITACHI, ZEISS, Tescan); technical developments essential to bioFEGSEM; cryobio FEGSEM; cryo-FIB; FEGSEM digital-tomography; array tomography; public health research; mammalian cells and tissues; digital challenges (image collection, storage, and automated data analysis); and more. Examines the creation of the biological field emission gun scanning electron microscopy (FEGSEM) and discusses its benefits to the biological research community and future value Provides insight into the design and development philosophy behind current instrument manufacturers Covers sample handling, applications, and key supporting techniques Focuses on the biological applications of field emission gun scanning electron

microscopy (FEGSEM), covering both plant and animal research Presented in full colour An important part of the Wiley-Royal Microscopical Series, Biological Field Emission Scanning Electron Microscopy is an ideal general resource for experienced academic and industrial users of electron microscopy—specifically, those with a need to understand the application, limitations, and strengths of FEGSEM.

scanning electron microscopy sample preparation: Sample Preparation Handbook for Transmission Electron Microscopy Jeanne Ayache, Luc Beaunier, Jacqueline Boumendil, Gabrielle Ehret, Danièle Laub, 2010-06-22 Successful transmission electron microscopy in all of its manifestations depends on the quality of the specimens examined. Biological specimen preparation protocols have usually been more rigorous and time consuming than those in the physical sciences. For this reason, there has been a wealth of scientific literature detailing specific preparation steps and numerous excellent books on the preparation of biological thin specimens. This does not mean to imply that physical science specimen preparation is trivial. For the most part, most physical science thin specimen preparation protocols can be executed in a matter of a few hours using straightforward steps. Over the years, there has been a steady stream of papers written on various aspects of preparing thin specimens from bulk materials. However, aside from several seminal textbooks and a series of book compilations produced by the Material Research Society in the 1990s, no recent comprehensive books on thin specimen preparation have appeared until this present work, first in French and now in English. Everyone knows that the data needed to solve a problem quickly are more important than ever. A modern TEM laboratory with supporting SEMs, light microscopes, analytical spectrometers, computers, and specimen preparation equipment is an investment of several million US dollars. Fifty years ago, electropolishing, chemical polishing, and replication methods were the principal specimen preparation methods.

scanning electron microscopy sample preparation: Scanning Electron Microscopy and X-Ray Microanalysis Joseph I. Goldstein, Dale E. Newbury, Joseph R. Michael, Nicholas W.M. Ritchie, John Henry J. Scott, David C. Joy, 2017-11-17 This thoroughly revised and updated Fourth Edition of a time-honored text provides the reader with a comprehensive introduction to the field of scanning electron microscopy (SEM), energy dispersive X-ray spectrometry (EDS) for elemental microanalysis, electron backscatter diffraction analysis (EBSD) for micro-crystallography, and focused ion beams. Students and academic researchers will find the text to be an authoritative and scholarly resource, while SEM operators and a diversity of practitioners — engineers, technicians, physical and biological scientists, clinicians, and technical managers — will find that every chapter has been overhauled to meet the more practical needs of the technologist and working professional. In a break with the past, this Fourth Edition de-emphasizes the design and physical operating basis of the instrumentation, including the electron sources, lenses, detectors, etc. In the modern SEM, many of the low level instrument parameters are now controlled and optimized by the microscope's software, and user access is restricted. Although the software control system provides efficient and reproducible microscopy and microanalysis, the user must understand the parameter space wherein choices are made to achieve effective and meaningful microscopy, microanalysis, and micro-crystallography. Therefore, special emphasis is placed on beam energy, beam current, electron detector characteristics and controls, and ancillary techniques such as energy dispersive x-ray spectrometry (EDS) and electron backscatter diffraction (EBSD). With 13 years between the publication of the third and fourth editions, new coverage reflects the many improvements in the instrument and analysis techniques. The SEM has evolved into a powerful and versatile characterization platform in which morphology, elemental composition, and crystal structure can be evaluated simultaneously. Extension of the SEM into a dual beam platform incorporating both electron and ion columns allows precision modification of the specimen by focused ion beam milling. New coverage in the Fourth Edition includes the increasing use of field emission guns and SEM instruments with high resolution capabilities, variable pressure SEM operation, theory, and measurement of x-rays with high throughput silicon drift detector (SDD-EDS) x-ray spectrometers. In addition to powerful vendor-supplied software to support data collection and processing, the

microscopist can access advanced capabilities available in free, open source software platforms, including the National Institutes of Health (NIH) ImageJ-Fiji for image processing and the National Institute of Standards and Technology (NIST) DTSA II for quantitative EDS x-ray microanalysis and spectral simulation, both of which are extensively used in this work. However, the user has a responsibility to bring intellect, curiosity, and a proper skepticism to information on a computer screen and to the entire measurement process. This book helps you to achieve this goal. Realigns the text with the needs of a diverse audience from researchers and graduate students to SEM operators and technical managers Emphasizes practical, hands-on operation of the microscope, particularly user selection of the critical operating parameters to achieve meaningful results Provides step-by-step overviews of SEM, EDS, and EBSD and checklists of critical issues for SEM imaging, EDS x-ray microanalysis, and EBSD crystallographic measurements Makes extensive use of open source software: NIH ImageJ-Fiji for image processing and NIST DTSA II for quantitative EDS x-ray microanalysis and EDS spectral simulation. Includes case studies to illustrate practical problem solving Covers Helium ion scanning microscopy Organized into relatively self-contained modules - no need to read it all to understand a topic Includes an online supplement—an extensive Database of Electron-Solid Interactions—which can be accessed on SpringerLink, in Chapter 3

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